


<b>Search Notes</b>  	<b>Application/Control No.</b>  10777290	<b>Applicant(s)/Patent Under Reexamination</b>  ZANK ET AL.
	<b>Examiner</b>  Chawan, Sheela C	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	119, 124, 125, 305,	6/24/07	SCC
455	562.1, 67.14, 69, 517, 466, 67.11, 423,522	"	"
235	380,375, 381, 376, 383,	"	"
370	310, 329, 342, 328, 277, 343, 442, 335	"	"
340	539.21, 539.1,539.21, 539.1, 539.13	"	"
382	119, 124	11/23/08	SCC
455	67.11	11/23/08	SCC
370	335	11/23/08	SCC
235	380	11/23/08	SCC
ABOVE SEARCH UP-DATE.		11/23/08	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATABASE, SEE THE PRINT OUT.	6/24/07	SCC
INVENTOR NAME SEARCH.	"	"
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY .	11/23/08	SCC
382/119, 124, 305.CCLS. US- PATENT TEXT SEARCH ONLY ,	11/23/08	SCC
455/ 562.1,67.14,69,517,466,67,11,423,522. CCLS. US-PATENT TEXT SEARCH ONLY.	11/23/08	SCC
370/310,329,342,328,277,343,442,335.CCLS. US-PATENT TEXT SEARCH ONLY.	11/23/08	SCC
340/539.21,539.1,537.13.CCLS. US-PATENT TEXT SEARCH ONLY.	11/23/08	SCC
INTERFERENCE SEARCH .	11/23/08	SCC
SEARCH IEEE OR INSPEC DATA BASE.	11/23/08	SCC
ABOVE SEARCH UP-DATE.	11/23/08	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	119, 124	11/23/08	SCC

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## INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
455	67.11	11/23/08	SCC
370	335	11/23/08	SCC
340	539.13	11/23/08	SCC

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